SLLS082B - DECEMBER 1978 - REVISED MAY 1995

<ul> <li>Meets or Exceeds the Requirement of ANSI EIA/TIA-422-B</li> </ul>	DW OR N PACKAGE (TOP VIEW)
<ul> <li>High-Impedance Output State for Party-Line Operation</li> </ul>	1A [ 1 20] V <sub>CC</sub>
<ul> <li>High Output Impedance in Power-Off Condition</li> </ul>	1Y
Low Input Current to Minimize Loading     Single 5 V Supply	1C   4 17   4Z CC   5 16   4C
<ul><li>Single 5-V Supply</li><li>40-mA Sink- and Source-Current Capability</li></ul>	2C [] 6 15 [] S 2Z [] 7 14 [] 3C
High-Speed Schottky Circuitry	2Y 🛮 8 13 🗓 3Z
Low Power Requirements	2A [ 9 12 ] 3Y GND [ 10 11 ] 3A

# description

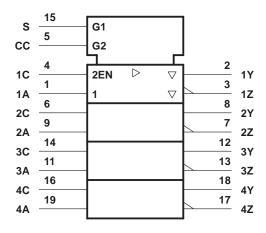
This line driver is designed to provide differential signals with high current capability on balanced lines. This circuit provides strobe and enable inputs to control all four drivers and provides an additional enable input for each driver. The output circuits have active pullup and pulldown resistors and are capable of sinking or sourcing 40 mA.

The SN75151 meets all requirements of ANSI EIA/TIA-422-B and Federal Standard 1020. The SN75151 is characterized for operation from 0°C to 70°C.

**FUNCTION TABLE** 

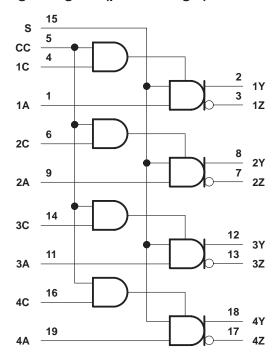
INPUTS					OUTPUTS	
ENABLE CC	ENABLE C	STROBE S	DATA A	Y	Z	
L	Х	Х	Х	Z	Z	
X	L	Χ	Χ	Z	Z	
Н	Н	L	Χ	L	Н	
Н	Н	Χ	L	L	Н	
Н	Н	Н	Н	Н	L	

# logic symbol<sup>†</sup>

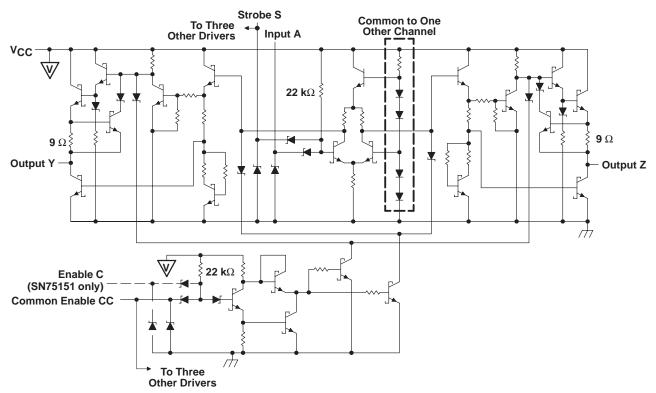


<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

# logic diagram (positive logic)



#### schematic



Resistor values shown are nominal.



# SN75151 QUADRUPLE DIFFERENTIAL LINE DRIVER

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# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub> (see Note 1)	7 V
Input voltage, V <sub>1</sub>	
Continuous total dissipation	tion Rating Table
Operating free-air temperature range, T <sub>A</sub>	0°C to 70°C
Storage temperature range, T <sub>stq</sub>	-65°C to 150°C
Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds	

NOTE 1: All voltage values, except differential output voltage V<sub>OD</sub>, are with respect to network ground terminal.

#### **DISSIPATION RATING TABLE**

PACKAGE T <sub>A</sub> ≤ 25°C POWER RATING		OPERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING		
DW	1125 mW	9.0 mW/°C	720 mW		
N	1150 mW	9.2 mW/°C	736 mW		

# recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>	4.75	5	5.25	V
High-level input voltage, VIH	2			V
Low-level input voltage, V <sub>IL</sub>			0.8	V
Common-mode output voltage, VOC	-0.25		6	V
High-level output current, IOH			-40	mA
Low-level output current, IOL			40	mA
Operating free-air temperature, T <sub>A</sub>	0		70	°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITI	ons†	MIN	TYP <sup>‡</sup>	MAX	UNIT
\/	lanut alama valtara	\/ MIN   10 mA	CC, S			-2	V
VIK	Input clamp voltage	$V_{CC} = MIN, I_{I} = -12 \text{ mA}$	All others		-0.9	-1.5	V
.,		V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX,	$I_{OH} = -20 \text{ mA}$	2.5			
VOH	High-level output voltage	V <sub>IH</sub> = 2 V	I <sub>OH</sub> = - 40 mA	2.4			V
VOL	Low-level output voltage	$V_{CC} = MIN, V_{IL} = MAX,$ $I_{OL} = 40 \text{ mA}$	V <sub>IH</sub> = 2 V,			0.5	٧
IVOD1	Differential output voltage	$V_{CC} = MAX, I_{O} = 0$			3.4	2V <sub>OD2</sub>	V
IVOD2l	Differential output voltage	V <sub>CC</sub> = MIN		2	2.8		V
ΔΙVODI	Change in magnitude of differential output voltage§	V <sub>CC</sub> = MIN			±0.01	±0.4	٧
V		VCC = MAX	$R_L$ = 100 Ω, See Figure 1		1.8	3	
Voc	Common-mode output voltage¶	V <sub>CC</sub> = MIN	See rigule r		1.6	3	V
∆IVocI	Change in magnitude of common- mode output voltage§	V <sub>CC</sub> = MIN or MAX			±0.02	±0.4	٧
	Off-state (high-impedance-state) output current	V <sub>CC</sub> = MAX, Enable at 0.8 V	V <sub>O</sub> = 0.5 V			-20	
IOZ			V <sub>O</sub> = 2.5 V			20	μА
			AO = ACC			20	
			V <sub>O</sub> = 6 V		0.1	100	
ΙO	Output current with power off	ACC = 0	$V_0 = -0.25 \text{ V}$		-0.1	-100	μΑ
			$V_0 = -0.25 \text{ V to 6 V}$			±100	
1 <sub>1</sub>	Input current at maximum input voltage	$V_{CC} = MAX$ , $V_I = 5.5 V$				0.1	mA
I	High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.4 V	C(SN75151), A			20	μА
lН		VCC = WAX,  V = 2.4  V	CC, S			80	μΑ
IIL	Low-level input current	$V_{CC} = MAX$ , $V_I = 0.4 V$	C(SN75151), A			-0.36	mA
''L	20W 10VOI IIIput Guiront	VOC - MI-VX, VI - 0.7 V	CC, S			-1.6	
los	Short-circuit output current#	VCC = MAX		-50	-90	-150	mA
lcc	Supply current (both drivers)	V <sub>CC</sub> = MAX, No load	Outputs disabled		30	60	mA
icc	Supply culterit (both univers)	1.00 11.00, 110 1000	Outputs enabled		60	80	'''' \

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

<sup>‡</sup> All typical values are at T<sub>A</sub> = 25°C and V<sub>CC</sub> = 5 V except for V<sub>OC</sub>, for which V<sub>CC</sub> is as stated under test conditions.

<sup>§</sup>  $\Delta |V_{OD}|$  and  $\Delta |V_{OC}|$  are the changes in magnitudes of  $V_{OD}$  and  $V_{OC}$ , respectively, that occur when the input is changed from a high level to a low level

In ANSI Standard EIA/TIA-422-B, VOC, which is the average of the two output voltages with respect to ground, is called output offset voltage, VOS.

<sup>#</sup>Only one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

# switching characteristics over recommended operating free-air temperature range, $V_{CC} = 5 \text{ V}$ (unless otherwise noted)

	PARAMETER	ER TEST CONDITIONS		MIN	TYP <sup>†</sup>	MAX	UNIT
<sup>t</sup> PLH	Propagation delay time, low- to high-level output	C <sub>L</sub> = 30 pF,	R <sub>L</sub> = 100 Ω,		15	30	ns
tPHL	Propagation delay time, high- to low-level output	Termination A,	See Figure 2		15	30	ns
<sup>t</sup> PLH	Propagation delay time, low- to high-level output	$C_L = 30 \text{ pF},$	Termination B,		13	25	ns
tPHL	Propagation delay time, high- to low-level output	See Figure 2			13	25	ns
tTLH	Transition time, low- to high-level output	C <sub>L</sub> = 30 pF,	= 30 pF, $R_1 = 100 \Omega$ ,		12	20	ns
tTHL	Transition time, high- to low-level output	Termination A,	See Figure 2		12	20	ns
<sup>t</sup> PZH	Output enable time to high level	C <sub>L</sub> = 30 pF, See Figure 3	$R_L = 60 \Omega$ ,		18	35	ns
tPZL	Output enable time to low level	C <sub>L</sub> = 30 pF, See Figure 4	R <sub>L</sub> = 111 Ω,		20	35	ns
tPHZ	Output disable time from high level	C <sub>L</sub> = 30 pF, See Figure 3	$R_L = 60 \Omega$ ,		19	30	ns
tPLZ	Output disable time from low level	C <sub>L</sub> = 30 pF, See Figure 4	$R_L = 111 \Omega$ ,		13	30	ns
	Overshoot factor	$R_L = 100 \Omega$ , See Figure 2	Termination C,			10	%

<sup>&</sup>lt;sup>†</sup> All typical values are at  $T_A = 25$ °C.

# PARAMETER MEASUREMENT INFORMATION

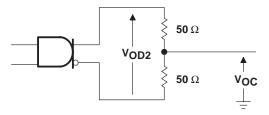
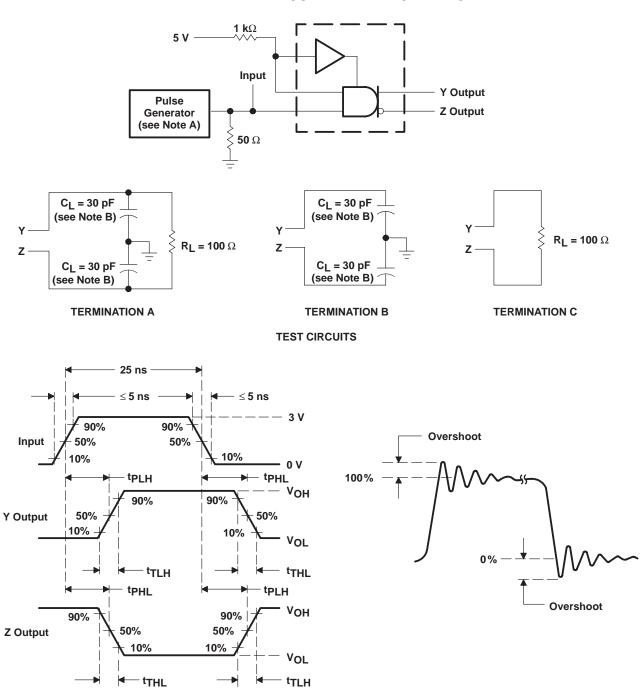


Figure 1. Differential and Common-Mode Output Voltages

# PARAMETER MEASUREMENT INFORMATION



**VOLTAGE WAVEFORMS** 

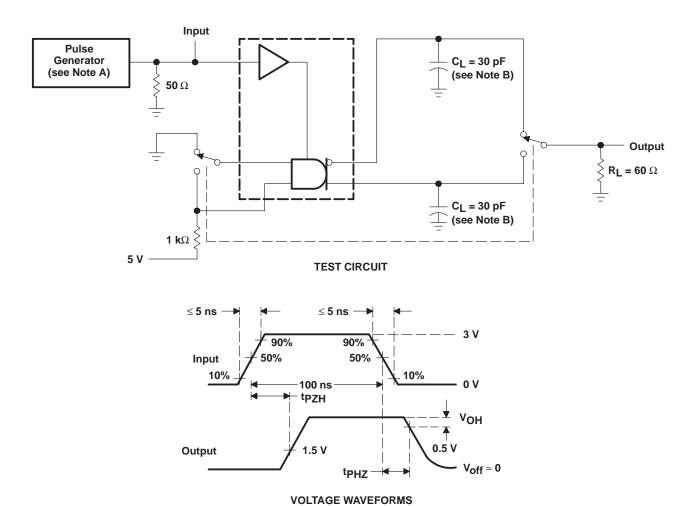
NOTES: A. The pulse generator has the following characteristics:  $Z_O$  = 50  $\Omega$ , PRR  $\leq$  10 MHz.

B. C<sub>L</sub> includes probe and jig capacitance.

Figure 2. Test Circuits, Voltage Waveforms, and Overshoot Factor



### PARAMETER MEASUREMENT INFORMATION

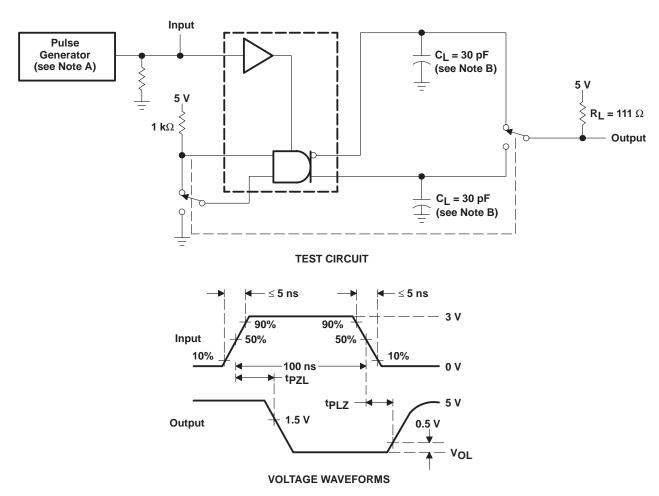


NOTES: A. The pulse generator has the following characteristics: Z<sub>O</sub> = 50  $\Omega$ , PRR  $\leq$  500 kHz.

B. C<sub>L</sub> includes probe and jig capacitance.

Figure 3. Test Circuit and Voltage Waveforms

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. The pulse generators have the following characteristics:  $Z_0$  = 50  $\Omega$ , PRR  $\leq$  500 kHz.

B. C<sub>L</sub> includes probe and jig capacitance.

Figure 4. Test Circuit and Voltage Waveforms

### TYPICAL CHARACTERISTICS

# Y OUTPUT VOLTAGE vs DATA INPUT VOLTAGE

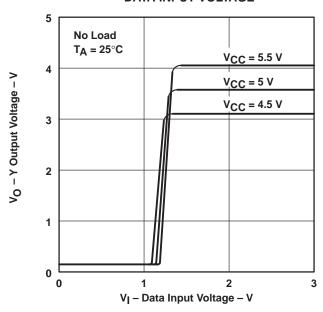
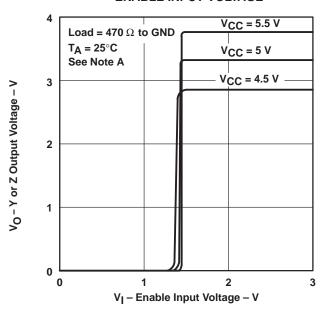


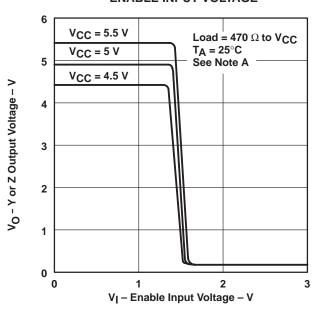
Figure 5

# Y OR Z OUTPUT VOLTAGE vs ENABLE INPUT VOLTAGE



NOTE A: The A input is connected to V<sub>CC</sub> during the testing of the Y outputs and to ground during testing of the Z outputs.

#### Y OR Z OUTPUT VOLTAGE vs ENABLE INPUT VOLTAGE

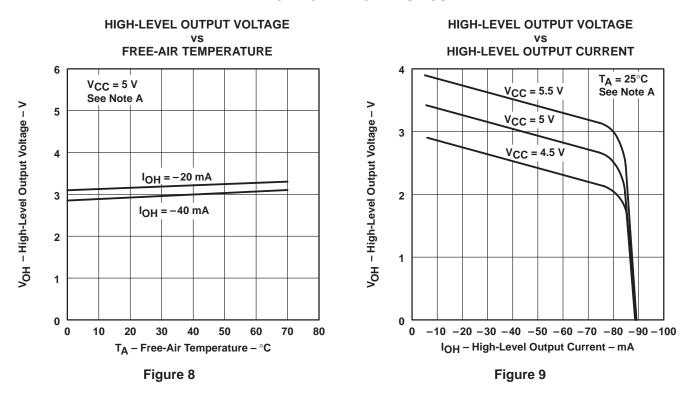


NOTE A: The A input is connected to GND during the testing of the Y outputs and to V<sub>CC</sub> during the testing of the Z outputs.

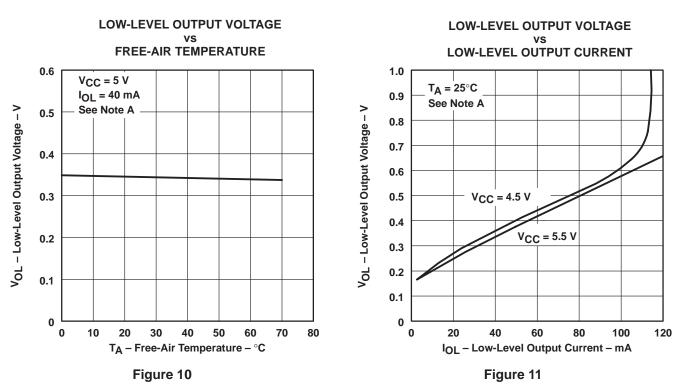
Figure 6 Figure 7



#### TYPICAL CHARACTERISTICS



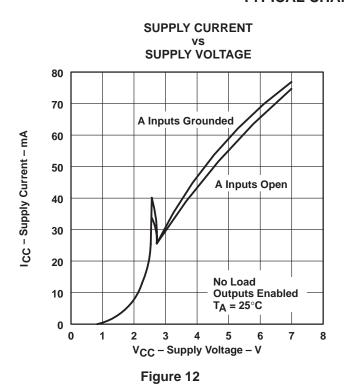
NOTE A: The A input is connected to VCC during the testing of the Y outputs and to ground during testing of the Z outputs.

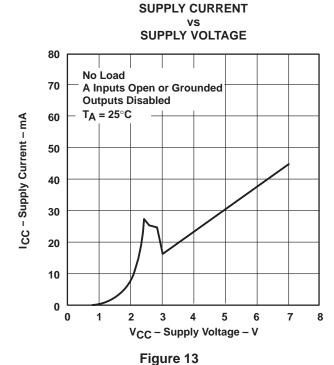


NOTE A: The A input is connected to GND during the testing of the Y outputs and to V<sub>CC</sub> during the testing of the Z outputs.



# **TYPICAL CHARACTERISTICS**





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